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	L4	L2 and (first with anneal\$3) and (second with anneal\$3)	200
	L3	L2 and ((two-step or two-stage) with anneal\$3)	11
	L2	L1 and implant\$5	2609
i	L1	((wafer or substrate) with bond\$3) and ((heat\$3 or anneal\$3 or thermal\$4) with (delaminat\$4 or detach\$4 or split\$4 or separat\$4 or cleav\$3 or bubbl\$2 or crack\$3))	20470

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	L9 and (thermal adj budget)							
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<u>L9</u>	smart adj cut	568	<u>L9</u>
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<u>L8</u>	6828216.pn.	1	<u>L8</u>
<u>L7</u>	6335258.pn.	1	<u>L7</u>
<u>L6</u>	L5 and (split\$4 or separat\$4 or cleav\$4 or detach\$4 or delaminat\$5)	317	<u>L6</u>
<u>L5</u>	L4 and (lower or less)	362	<u>L5</u>
<u>L4</u>	L3 and thermal	397	<u>L4</u>
<u>L3</u>	L2 and (hydrogen or ion)	487	<u>L3</u>
<u>L2</u>	L1 and temperature and time	721	<u>L2</u>
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